

# Near-field optical imaging of monolayer MoS<sub>2</sub> grown by chemical vapor deposition: Identification of grain boundaries and line defects

Yongjun Lee<sup>1,2</sup>, Seki Park<sup>1,2</sup>, Min Su Kim<sup>1</sup>, Hyun Kim<sup>1,2</sup>, Jubok Lee<sup>1,2</sup>, Young Hee Lee<sup>1,2,3</sup> and Jeongyong Kim<sup>1,2\*</sup>

<sup>1</sup>Center for Integrated Nanostructure Physics (CINAP), Institute for Basic Science (IBS), Sungkyunkwan University, Suwon 446-746, Korea

<sup>2</sup>Department of Energy Science, Sungkyunkwan University, Suwon 440-746, Republic of Korea

<sup>3</sup>Department of Physics, Sungkyunkwan University, Suwon 440-746, Republic of Korea

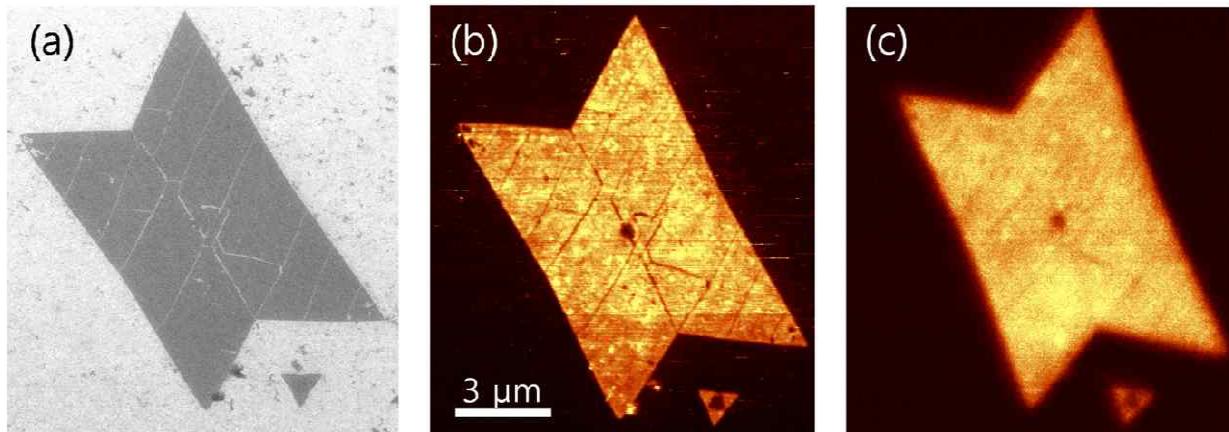
[j.kim@skku.edu](mailto:j.kim@skku.edu)

## Abstract

Molybdenum disulphide (MoS<sub>2</sub>), as known as 2-dimensional transition metal dichalcogenides, has appeared as semiconductor with an indirect/direct band gap in the range 1.2 - 1.8 eV, which shows the photoluminescence (PL) depending on the thickness of the layers. Moreover, large-area monolayer MoS<sub>2</sub> by the chemical vapor deposition method paves the way to promising optoelectronic applications. However, imperfections such as grain boundaries and line defects in grown MoS<sub>2</sub> induces the lower mobility than the mechanically exfoliated MoS<sub>2</sub> and the degradation of optical properties. Therefore the visualization of such imperfections have been limited to scanning tunneling microscopy, transmission electron microscopy and second harmonic generation.

Here, we used near-field scanning optical microscope (NSOM) PL imaging of monolayer MoS<sub>2</sub> with 100 nm spatial resolution and showed that NSOM PL imaging can identify the nano-scale line defects, as small as ~20 nm in width, developed on grain boundaries of CVD grown monolayer MoS<sub>2</sub>, which were not distinguished by conventional confocal PL imaging. We also found that combined with correlated scanning electron microscope (SEM) imaging, grain boundaries without formation of physical line-defects didn't provide the detectable PL contrast even with NSOM imaging.

## Figures



Figures. (a) The image of butterfly shaped MoS<sub>2</sub> taken by SEM. and The PL images taken by (b) NSOM and (c) Confocal.